

Notice of References Cited

Application/Control No. 09/756,420	Applicant(s)/Patent Under Reexamination HAYASHI ET AL.		
Examiner	Art Unit	Page 1 of 1	
Cheukfan Lee	2622	Page 1 of 1	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,769,515	06-1998	Chang, Yao-Wen	312/223.2
	В	US-6,529,294	03-2003	Chang, Ching-Chung	358/471
	С	US-5,767,977	06-1998	Thelen et al.	358/296
-	D	US-6,305,676	10-2001	Peng, Sheng Yeh	267/160
	E	US-6,700,717	03-2004	Lee, Andy	359/896
	F	US-6,450,727	09-2002	Lu, Jih-Yung	403/322.1
	G	US-5,973,866	10-1999	Tseng, Jacky	359/896
	Н	US-6,247,374	06-2001	Tseng, Jacky	74/89.22
	ı	US-			
	J	US-			
	к	US-			
	L	US-			
	М	,US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	v	·
	w	
	×	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.